Search Notes



App	lica	tion	Conti	rol No
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10591152

Reexamination

NAKAHARA ET AL.

Applicant(s)/Patent Under

Examiner

Art Unit

LEON-VIET Q NGUYEN

2611

SEARCHED

Class	Subclass	Date	Examiner
327	140, 159	8/19/09	LVN
375	355	8/19/09	LVN

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Search Notes	Date	Examiner
inventor name search for double patenting in EAST	8/19/09	LVN
EAST search history	8/17/09-8/19/09,	LVN
	1/28/10	

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
327	140, 159	1/28/10	LVN
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